

Docket No.: 4590-337

PATENT

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Emmanuel DE CHAMBOST et al.

Confirmation No.

U.S. Patent Application No. *not yet assigned*Filed: *herewith*For: DEVICE FOR MEASURING THE EMISSION OF X RAYS PRODUCED BY AN OBJECT  
EXPOSED TO AN ELECTRON BEAMINFORMATION DISCLOSURE STATEMENTCommissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed with the application and no certification or fee is required.

Please note this is a PCT application in the entry of the National Phase in the U.S. and copies of the references cited were transmitted by WIPO and are believed to be in the file of the above-identified application and readily available to the Examiner. Therefore it is believed that Applicants have met all requirements regarding duty of disclosure under 37 CFR 1.56. A copy of the foreign search report is attached for the Examiner's information. Acknowledgement and consideration of these documents are respectfully requested.

Respectfully submitted,

LOWE HAUPTMAN GILMAN &amp; BERNER, LLP

Kenneth M. Berner  
Registration No. 37,0931700 Diagonal Road, Suite 310  
Alexandria, Virginia 22314  
(703) 684-1111 KMB/eb  
Facsimile: (703) 518-5499  
Date: September 23, 2004

<b>INFORMATION DISCLOSURE          CITATION IN AN          APPLICATION          (PTO-1449)</b>	ATTY. DOCKET NO. <b>4590-337</b>	U.S. APPLICATION NO. <b>Not yet assigned</b>
	APPLICANT <b>Emmanuel DE CHAMBOST et al.</b>	
	FILING DATE <b>herewith</b>	GROUP

U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
	<b>3 760 180 A</b>	<b>09/18/1973</b>	<b>WEBER</b>			
	<b>5 714 757 A</b>	<b>02/03/1998</b>	<b>OSABE et al</b>			

FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
	<b>01 95365 A</b>	<b>12/13/2001</b>	<b>WO</b>				

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER	DATE CONSIDERED
----------	-----------------

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.